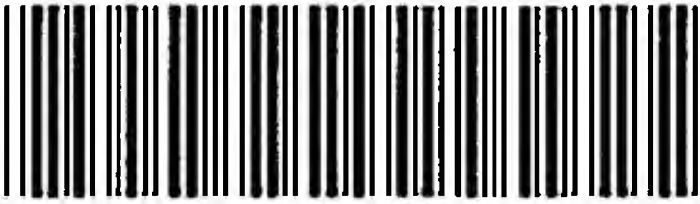


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,847	YAN, HAI	
	Examiner	Art Unit	
	Helen C. Kwok	2856	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
73	504.04	3/22/2005	HK
73	504.14	3/22/2005	HK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated Previous Search	3/22/2005	HK